

HC3906

30V N-Channel MOSFET

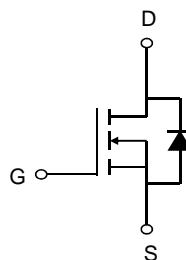
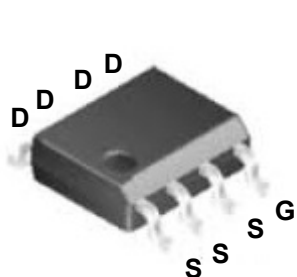
General Description

These N-Channel enhancement mode power field effect transistors are using trench DMOS technology. This advanced technology has been especially tailored to minimize on-state resistance, provide superior switching performance, and withstand high energy pulse in the avalanche and commutation mode. These devices are well suited for high efficiency fast switching applications.

Features

V_{DS}	30V
I_D (at $V_{GS}=10V$)	20A
$R_{DS(ON)}$ (at $V_{GS}=10V$)	5.0m Ω (Type)

SOP8



Absolute Maximum Ratings $T_A=25^{\circ}C$ unless otherwise noted

Parameter	Symbol	Maximum	Units	
Drain-Source Voltage	V_{DS}	30	V	
Gate-Source Voltage	V_{GS}	± 20	V	
Drain Current-Continuous	TC=25 $^{\circ}C$	I_D	20	A
	TC=100 $^{\circ}C$	I_D	12.6	A
Drain Current – Pulsed	I_{DM}	80	A	
Maximum Power Dissipation	P_D	5.4	W	
Junction and Storage Temperature Range	T_J, T_{STG}	-55 To 150	$^{\circ}C$	

Thermal Characteristics

Parameter	Symbol	Typ	Max	Unit
Thermal Resistance junction-case	$R_{\theta Jc}$		1.1	$^{\circ}C/W$
Thermal Resistance unction-to-Ambient	$R_{\theta JA}$		60	$^{\circ}C/W$

Electrical Characteristics (T_J=25°C unless otherwise noted)

Symbol	Parameter	Condition	Min	Typ	Max	Unit
STATIC PARAMETERS						
BV _{DSS}	Drain-Source Breakdown Voltage	V _{GS} =0V, I _D =250μA	30			V
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} =30V, V _{GS} =0V			1	μA
I _{GSS}	Gate-Body Leakage Current	V _{GS} =±20V, V _{DS} =0V			±100	nA
V _{GS(th)}	Gate Threshold Voltage	V _{DS} =V _{GS} , I _D =250μA	1.0	1.6	2.5	V
R _{DS(ON)}	Drain-Source On-State Resistance	V _{GS} =10V, I _D =10A		5.0	6.0	mΩ
		V _{GS} =4.5V, I _D =5A		6.8	9.0	mΩ
DYNAMIC PARAMETERS						
C _{ISS}	Input Capacitance	V _{DS} =15V, V _{GS} =0V, F=1.0MHz		1160		pF
C _{OSS}	Output Capacitance			200		pF
C _{RSS}	Reverse Transfer Capacitance			180		pF
SWITCHING PARAMETERS						
t _{d(on)}	Turn-on Delay Time	V _{GS} =10V V _{DS} =15V R _L =0.75Ω R _{GEN} =3Ω		7.3		nS
t _r	Turn-on Rise Time			14.5		nS
t _{d(off)}	Turn-Off Delay Time			35.8		nS
t _f	Turn-Off Fall Time			9.6		nS
Q _g	Total Gate Charge	V _{DS} =15V, I _D =4.5A, V _{GS} =4.5V		11		nC
Q _{gs}	Gate-Source Charge			1.85		nC
Q _{gd}	Gate-Drain Charge			6.8		nC
V _{SD}	Diode Forward Voltage	V _{GS} =0V, I _{SD} =1A		0.72	1.3	V
R _g	Gate resistance	V _{GS} =0V, V _{DS} =0V, F=1MHz		2.5		Ω

Note:

1. Repetitive Rating : Pulsed width limited by maximum junction temperature.
2. The data tested by pulsed , pulse width ≅ 300us , duty cycle ≅ 2%.
3. Essentially independent of operating temperature.

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

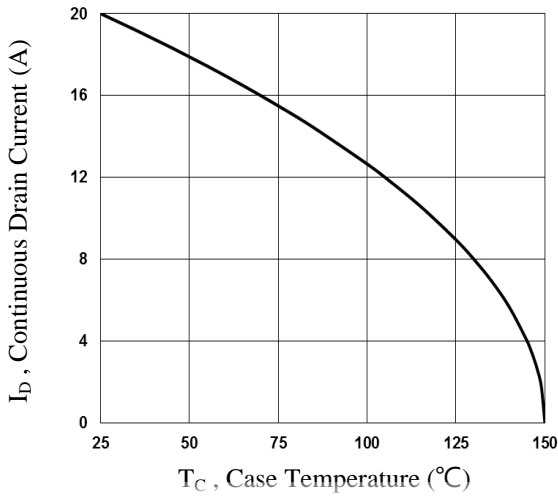


Fig.1 Continuous Drain Current vs. T_C

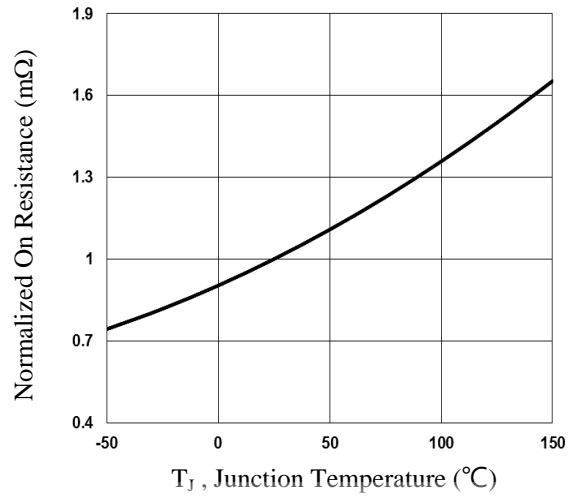


Fig.2 Normalized $R_{DS(on)}$ vs. T_J

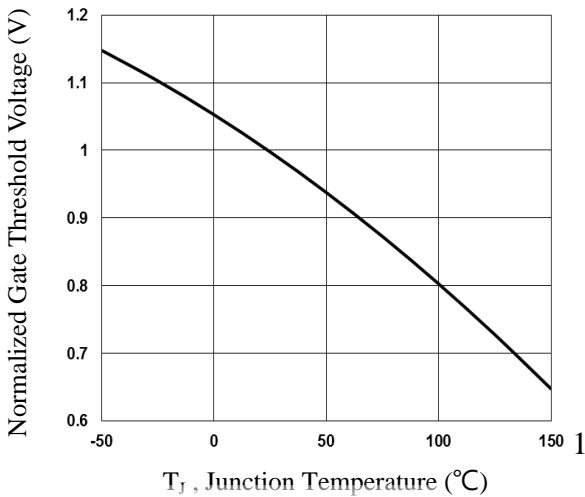


Fig.3 Normalized V_{th} vs. T_J

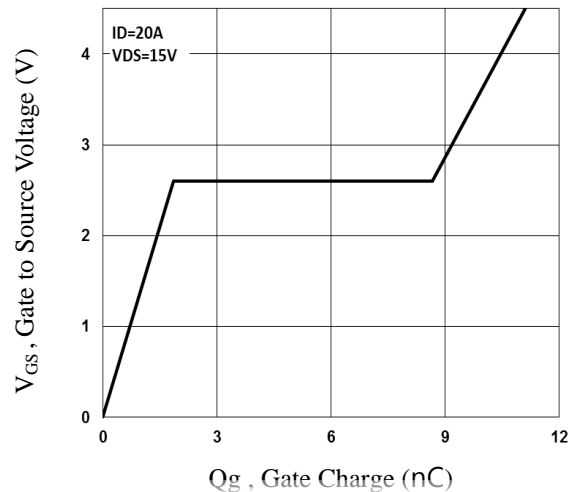


Fig.4 Gate Charge Waveform

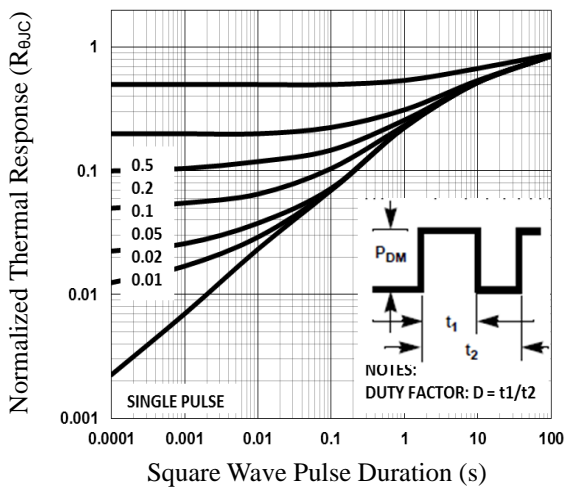


Fig.5 Normalized Transient Impedance

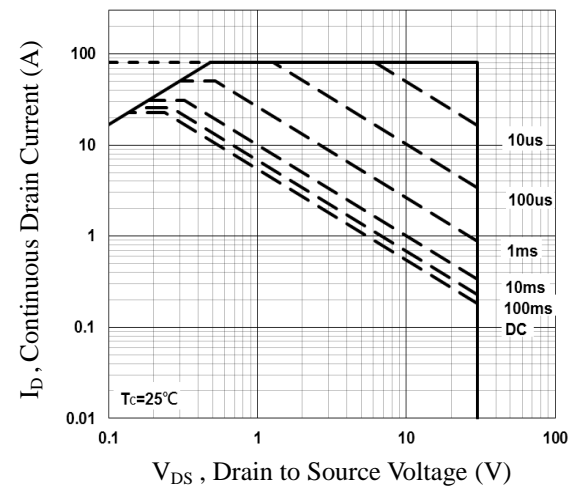


Fig.6 Maximum Safe Operation Area

TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS

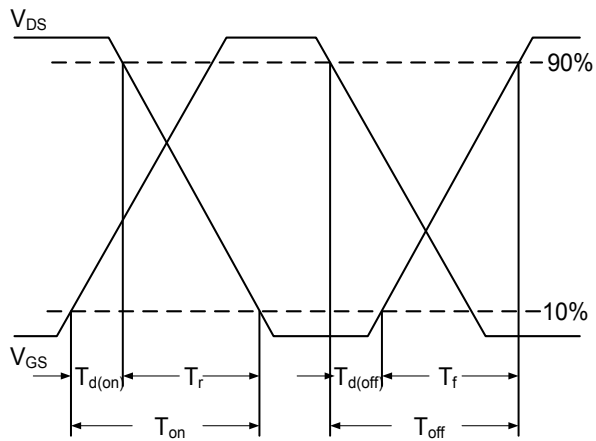


Fig.7 Switching Time Waveform

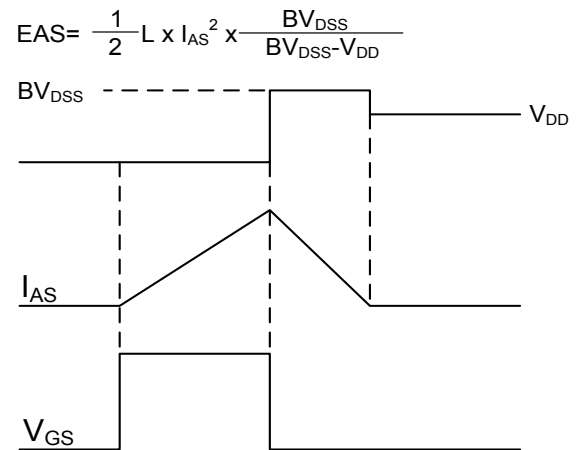
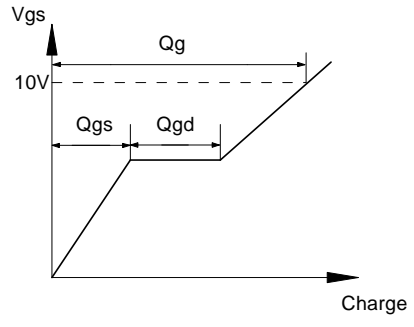
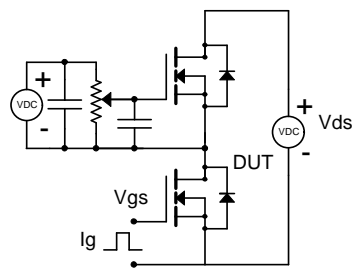
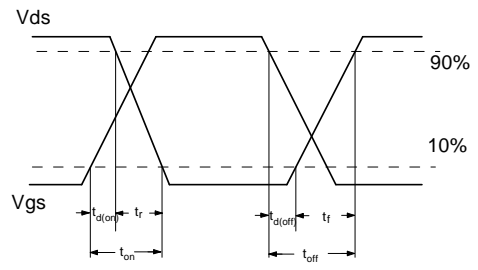
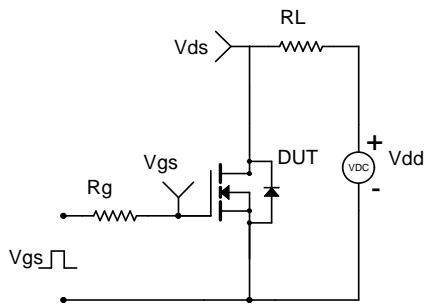


Fig.8 EAS Waveform

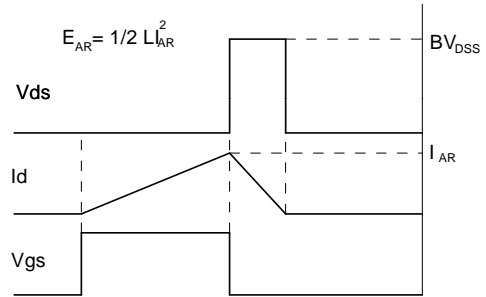
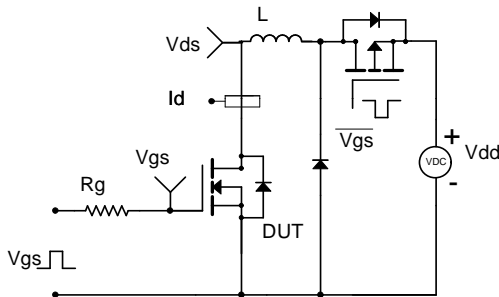
Gate Charge Test Circuit & Waveform



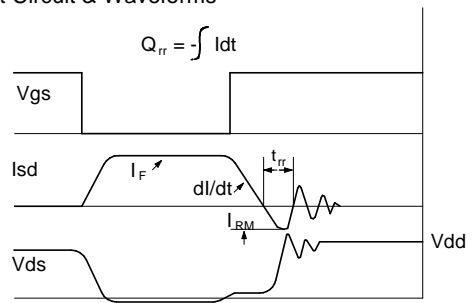
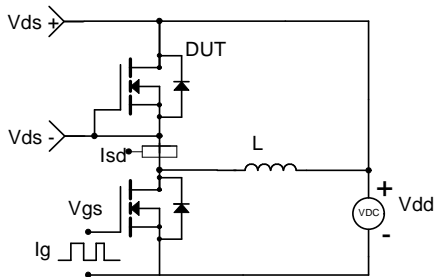
Resistive Switching Test Circuit & Waveforms



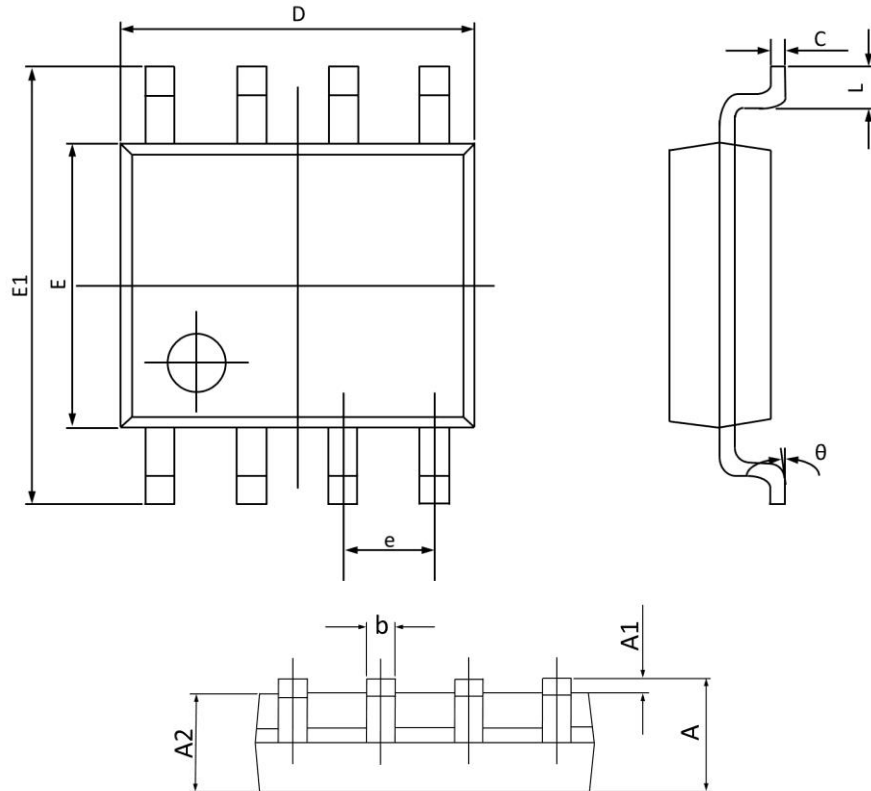
Unclamped Inductive Switching (UIS) Test Circuit & Waveforms



Diode Recovery Test Circuit & Waveforms



SOP8 PACKAGE INFORMATION



Symbol	Dimensions In Millimeters		Dimensions In Inches	
	MAX	MIN	MAX	MIN
A	1.750	1.350	0.069	0.053
A1	0.250	0.100	0.010	0.004
A2	1.500	1.300	0.059	0.051
b	0.490	0.350	0.019	0.014
C	0.260	0.190	0.010	0.007
D	5.100	4.700	0.201	0.185
E	4.100	3.700	0.161	0.146
E1	6.200	5.800	0.244	0.228
e	1.27BSC		0.05BSC	
L	0.900	0.400	0.035	0.016
theta	8°	0°	8°	0°